I claim:

1.   A method for determining patent license fee data, comprising:

inputting on a computer patent license data;

processing the patent license data using an interaction involving the

5   computer to determine patent license fee data; and

outputting on the computer the patent license fee data,

wherein the processing step includes determining algorithmically exposure

rate data to be applied in determining the patent license fee data.

2.   The method according to claim 1, wherein the processing step

10   includes determining exposure rate data to be applied in determining the patent

license fee data in function of a patent count.

3.   The method according to claim 1, wherein the processing step

includes determining exposure rate data to be applied in determining the patent

license fee data in function of a patent strength metric.

15   4.   The method according to claim 1, wherein the processing step

includes determining exposure rate data to be applied in determining the patent

license fee data in function of a patent count and a patent strength metric.

5.   A networked computing system, comprising an end-user station

having a user interface, for interacting with a user, and a network interface, for

20   interacting with a network, wherein the end-user station interacts with the user

and the network to determine patent license fee data including determining

algorithmically exposure rate data to be applied in determining the patent license fee data.

6.   The system according to claim 5, wherein the exposure rate data are determined in function of a patent count.

7.   The system according to claim 5, wherein the exposure rate data are determined in function of a patent strength metric.

8.   The system according to claim 5, wherein the exposure rate data are determined in function of a patent count and a patent strength metric.

9.   A computer program having instructions for interacting with an end-user station, a user and a network to determine patent license fee data including determining algorithmically exposure rate data to be applied in determining the patent license fee data.

10.   The program according to claim 9, wherein the exposure rate data are determined in function of a patent count.

11.   The program according to claim 9, wherein the exposure rate data are determined in function of a patent strength metric.

12.   The program according to claim 9, wherein the exposure rate data are determined in function of a patent count and a patent strength metric.

13.   A method for determining patent license fee data, comprising:

identifying a patent count;

calculating exposure rate data in function of the patent count;

calculating patent license fee data in function of the exposure rate data.

14.   The method according to claim 13, further comprising:

identifying a patent strength metric,

wherein the exposure rate data are calculated in further function of the

patent strength metric.

5   15.   A method for determining exposure rate data for application in

determining patent license fee data, comprising:

identifying a plurality of exposure rate function parameters;

defining an exposure rate function using the plurality of exposure rate

function parameters;

10   identifying a patent count; and

applying the patent count in the exposure rate function to determine

exposure rate data.

16.   The method according to claim 15, further comprising:

identifying a patent strength parameter; and

15   adjusting the exposure rate function using the patent strength parameter

prior to applying the patent count in the exposure rate function.

17.   The method according to claim 15, wherein the exposure rate

function parameters include a minimum patent threshold and a per patent

exposure rate.

20   18.   The method according to claim 15, wherein the plurality of

exposure rate function parameters includes a per patent exposure rate and a

maximum patent threshold.

19.	The method according to claim 15, wherein the plurality of exposure rate function parameters includes a minimum patent threshold and a maximum patent threshold.

20.	The method according to claim 15, wherein the plurality of

5	exposure rate function parameters includes a maximum exposure rate.

21.	The method according to claim 15, wherein the exposure rate function is linear.